64K x 4 Bit Static RAM

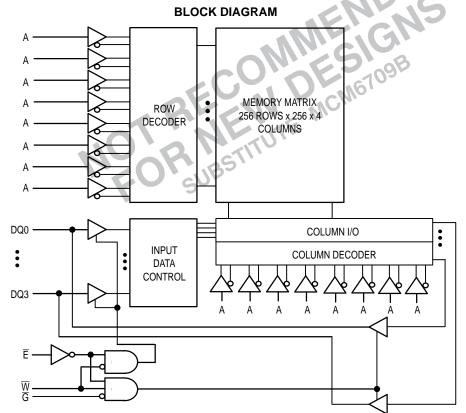
The MCM6709A is a 262,144 bit static random access memory organized as 65,536 words of 4 bits, fabricated using high–performance silicon–gate BiCMOS technology. Static design eliminates the need for external clocks or timing strobes.

Output enable $(\overline{\mathbf{G}})$ provides increased system flexibility and eliminates bus contention problems.

The MCM6709A is available in a 300 mil, 28 lead plastic surface—mount SOJ package.

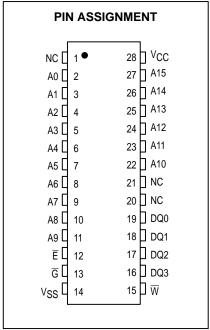
- Single 5 V ± 10% Power Supply
- Fully Static No Clock or Timing Strobes Necessary
- · All Inputs and Outputs are TTL Compatible
- Three State Outputs
- · Fast Access Times:

MCM6709A-8 = 8 ns MCM6709A-10 = 10 ns MCM6709A-12 = 12 ns



MCM6709A





DINI NIA MEC

5/95



TRUTH TABLE (X = Don't Care)

E	G	W	Mode	Output	Cycle
Н	Х	Х	Not Selected	High-Z	_
L	Н	Н	Read	High-Z	_
L	L	Н	Read	D _{out}	Read Cycle
L	Х	L	Write	D _{in}	Write Cycle

ABSOLUTE MAXIMUM RATINGS (See Note)

Rating	Symbol	Value	Unit
Power Supply Voltage	Vcc	- 0.5 to + 7.0	V
Voltage Relative to VSS for Any Pin Except VCC	V _{in} , V _{out}	- 0.5 to V _{CC} + 0.5	V
Output Current (per I/O)	l _{out}	± 30	mA
Power Dissipation	PD	2.0	W
Temperature Under Bias	T _{bias}	- 10 to + 85	°C
Operating Temperature	TA	0 to + 70	°C
Storage Temperature — Plastic	T _{stg}	- 55 to + 125	°C

NOTE: Permanent device damage may occur if ABSOLUTE MAXIMUM RATINGS are exceeded. Functional operation should be restricted to RECOMMENDED OPER-ATING CONDITIONS. Exposure to higher than recommended voltages for extended periods of time could affect device reliability.

This device contains circuitry to protect the inputs against damage due to high static voltages or electric fields; however, it is advised that normal precautions be taken to avoid application of any voltage higher than maximum rated voltages to this high-impedance circuit.

This BiCMOS memory circuit has been designed to meet the dc and ac specifications shown in the tables, after thermal equilibrium has been established. The circuit is in a test socket or mounted on a printed circuit board and transverse air flow of at least 500 linear feet per minute is maintained.

DC OPERATING CONDITIONS AND CHARACTERISTICS

 $(V_{CC} = 5.0 \text{ V} \pm 10\%, T_A = 0 \text{ to } 70^{\circ}\text{C}, \text{Unless Otherwise Noted})$

RECOMMENDED OPERATING CONDITIONS

Parameter	Symbol	Min	Тур	Max	Unit
Supply Voltage (Operating Voltage Range)	Vcc	4.5	5.0	5.5	V
Input High Voltage	V _{IH}	2.2	_	V _{CC} + 0.3*	V
Input Low Voltage	V _{IL}	- 0.5**	_	0.8	V

^{*} V_{IH} (max) = V_{CC} + 0.3 V dc; V_{IH} (max) = V_{CC} + 2.0 V ac (pulse width \leq 2.0 ns) or I \leq 30.0 mA.

DC CHARACTERISTICS

Parameter	Symbol	Min	Max	Unit
Input Leakage Current (All Inputs, V _{in} = 0 to V _{CC})	llkg(l)	_	± 1.0	μΑ
Output Leakage Current ($\overline{E} = V_{IH}$, $V_{out} = 0$ to V_{CC})	I _{lkg(O)}	_	± 1.0	μΑ
Output High Voltage (I _{OH} = - 4.0 mA)	Voн	2.4	_	V
Output Low Voltage (I _{OL} = 8.0 mA)	V _{OL}	_	0.4	V

POWER SUPPLY CURRENTS

Parameter	Symbol	MCM6709A-8	MCM6709A-10	MCM6709A-12	Unit	Notes
AC Active Supply Current ($I_{Out} = 0 \text{ mA}$, $V_{CC} = \text{max}$, $f = f_{max}$)	ICCA	185	175	165	mA	1, 2, 3
AC Standby Current ($\overline{E} = V_{IH}$, $V_{CC} = max$, $f = f_{max}$)	I _{SB1}	120	110	105	mA	1, 2, 3
$ \begin{array}{l} \textbf{CMOS Standby Current (V_{CC} = max, f = 0 MHz,} \\ \hline \textbf{E} \geq \textbf{V}_{CC} - 0.2 \text{ V, V}_{in} \leq \textbf{V}_{SS}, \text{ or } \geq \textbf{V}_{CC} - 0.2 \text{ V)} \end{array} $	ISB2	50	50	50	mA	

NOTES:

- 1. Reference AC Operating Conditions and Characteristics for input and timing (V_{IH}/V_{IL}, t_I/t_f, pulse level 0 to 3.0 V, V_{IH} = 3.0 V).
- 2. All addresses transition simultaneously low (LSB) and then high (MSB).
- 3. Data states are all zero.

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^{**} V_{IL} (min) = -0.5 V dc @ 30.0 mA; V_{IL} (min) = -2.0 V ac (pulse width \leq 2.0 ns) or $I \leq$ 30.0 mA.

CAPACITANCE (f = 1.0 MHz, dV = 3.0 V, T_A = 25°C, Periodically Sampled Rather Than 100% Tested)

Parameter	Symbol	Max	Unit
Address Input Capacitance	C _{in}	5	pF
Control Pin Input Capacitance (E, G, W)	C _{in}	5	pF
Input/Output Capacitance	C _{I/O}	6	pF

AC OPERATING CONDITIONS AND CHARACTERISTICS

(V_{CC} = $5.0 \text{ V} \pm 10\%$, T_A = $0 \text{ to} + 70^{\circ}\text{C}$, Unless Otherwise Noted)

Input Timing Measurement Reference Level 1.5 V	Output Timing Measurement Reference Level 1.5 V
Input Pulse Levels 0 to 3.0 V	Output Load See Figure 1A
Input Rise/Fall Time	

READ CYCLES 1 AND 2 (See Notes 1 and 2)

		MCM6709A-8		MCM6709A-10		MCM6709A-12			
Parameter	Symbol	Min	Max	Min	Max	Min	Max	Unit	Notes
Read Cycle Time	^t AVAV	8	_	10	_	12	_	ns	3
Address Access Time	^t AVQV	_	8	_	10	_	12	ns	
Chip Enable Access Time	^t ELQV	_	8	_	10	_	12	ns	
Output Enable Access Time	^t GLQV	_	4	_	5	_	6	ns	
Output Hold from Address Change	^t AXQX	3	_	3	_	3	_	ns	
Chip Enable Low to Output Active	^t ELQX	1	_	1	_	1	_	ns	4, 5, 6
Output Enable Low to Output Active	^t GLQX	0	_	0	_	0	_	ns	4, 5, 6
Chip Enable High to Output High–Z	^t EHQZ	0	4.5	0	5	0	6	ns	4, 5, 6
Output Enable High to Output High–Z	^t GHQZ	0	4	0	5	0	6	ns	4, 5, 6

NOTES:

- 1. W is high for read cycle.
- 2. Product sensitivities to noise require proper grounding and decoupling of power supplies as well as minimization or elimination of bus contention conditions during read and write cycles.
- 3. All read cycle timings are referenced from the last valid address to the first transitioning address.
- 4. At any given voltage and temperature, t_{EHQZ} max is less than t_{ELQX} min, and t_{GHQZ} max is less than t_{GLQX} min, both for a given device and from device to device.
- 5. Transition is measured 200 mV from steady-state voltage with load of Figure 1B.
- 6. This parameter is sampled and not 100% tested.

AC TEST LOADS

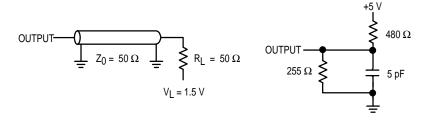


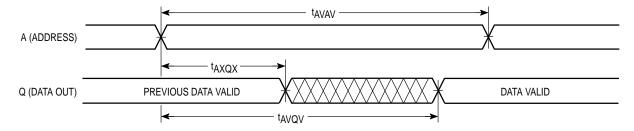
Figure 1A Figure 1B

TIMING LIMITS

The table of timing values shows either a minimum or a maximum limit for each parameter. Input requirements are specified from the external system point of view. Thus, address setup time is shown as a minimum since the system must supply at least that much time (even though most devices do not require it). On the other hand, responses from the memory are specified from the device point of view. Thus, the access time is shown as a maximum since the device never provides data later than that time.

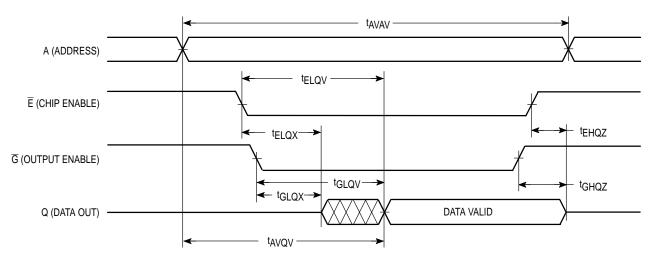
MOTOROLA FAST SRAM MCM6709A

READ CYCLE 1 (See Note)



NOTE: Device is continuously selected (\overline{E} = V_{IL}, \overline{G} = V_{IL}).

READ CYCLE 2 (See Note)



NOTE: Addresses valid prior to or coincident with $\overline{\mathsf{E}}$ going low.

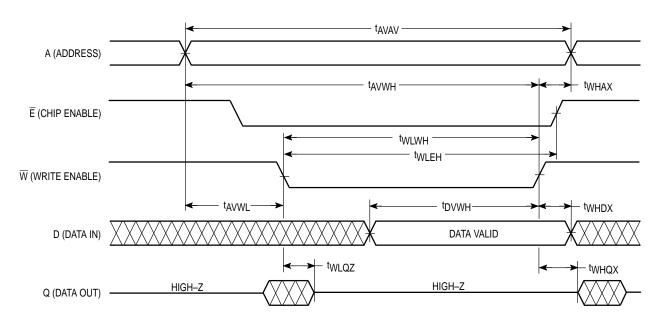
WRITE CYCLE 1 (W Controlled, See Notes 1 and 2)

		мсм6	709A-8	MCM6709A-10		MCM6709A-12			
Parameter	Symbol	Min	Max	Min	Max	Min	Max	Unit	Notes
Write Cycle Time	t _{AVAV}	8		10	_	12	_	ns	3
Address Setup Time	^t AVWL	0		0	_	0	_	ns	
Address Valid to End of Write	^t AVWH	8	_	9	_	10	_	ns	
Write Pulse Width	tWLWH, tWLEH	8	_	9	_	10	_	ns	
Data Valid to End of Write	^t DVWH	4	_	5	_	6	_	ns	
Data Hold Time	tWHDX	0	_	0	_	0	_	ns	
Write Low to Data High–Z	tWLQZ	0	4	0	5	0	6	ns	4, 5, 6
Write High to Output Active	tWHQX	3	_	3	_	3	_	ns	4, 5, 6
Write Recovery Time	tWHAX	0	_	0	_	0	_	ns	

NOTES:

- 1. A write occurs during the overlap of \overline{E} low and \overline{W} low.
- 2. Product sensitivities to noise require proper grounding and decoupling of power supplies as well as minimization or elimination of bus contention conditions during read and write cycles.
- 3. All write cycle timing is referenced from the last valid address to the first transitioning address.
- 4. Transition is measured 200 mV from steady state voltage with load of Figure 1B.
- 5. This parameter is sampled and not 100% tested.
- 6. At any given voltage and temperature, twLQz max is less than twHQx min both for a given device and from device to device.

WRITE CYCLE 1



MOTOROLA FAST SRAM MCM6709A

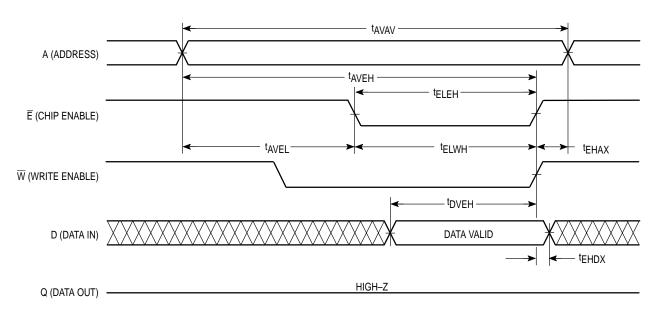
WRITE CYCLE 2 (E Controlled, See Notes 1 and 2)

		MCM6709A-8 MCM6709A-1		09A-10	MCM6709A-12				
Parameter	Symbol	Min	Max	Min	Max	Min	Max	Unit	Notes
Write Cycle Time	t _{AVAV}	8	_	10	_	12	_	ns	3
Address Setup Time	^t AVEL	0	_	0	_	0	_	ns	
Address Valid to End of Write	^t AVEH	8	_	9	_	10	_	ns	
Chip Enable to End of Write	tELEH, tELWH	7	_	8	_	9	_	ns	4, 5
Data Valid to End of Write	^t DVEH	4	_	5	_	6	_	ns	
Data Hold Time	^t EHDX	0	_	0	_	0	_	ns	
Write Recovery Time	^t EHAX	0	_	0	_	0	_	ns	

NOTES:

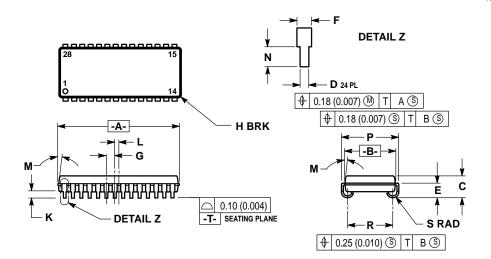
- 1. A write occurs during the overlap of \overline{E} low and \overline{W} low.
- 2. Product sensitivities to noise require proper grounding and decoupling of power supplies as well as minimization or elimination of bus contention conditions during read and write cycles.
- 3. All write cycle timing is referenced from the last valid address to the first transitioning address.
- 4. If \overline{E} goes low coincident with or after \overline{W} goes low, the output will remain in a high impedance condition.
- 5. If \overline{E} goes high coincident with or before \overline{W} goes high, the output will remain in a high impedance condition.

WRITE CYCLE 2



PACKAGE DIMENSIONS

J PACKAGE 300 MIL SOJ CASE 810B-03



- NOTES:
 1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
 2. DIMENSION A & B DO NOT INCLUDE MOLD PROTRUSION. MOLD PROTRUSION SHALL NOT EXCEED 0.15 (0.006) PER SIDE.
 3. CONTROLLING DIMENSION: INCH.
 4. DIM R TO BE DETERMINED AT DATUM -T.
 5. 810B-01 AND -02 OBSOLETE, NEW STANDARD 810B-03.

	MILLIM	ETERS	INC	HES	
DIM	MIN	MAX	MIN	MAX	
Α	18.29	18.54	0.720	0.730	
В	7.50	7.74	0.295	0.305	
С	3.26	3.75	0.128	0.148	
D	0.39	0.50	0.015	0.020	
E	2.24	2.48	0.088	0.098	
F	0.67	0.81	0.026	0.032	
G	1.27	BSC	0.050 BSC		
Н	_	0.50	_	0.020	
K	0.89	1.14	0.035	0.045	
L	0.64	BSC	0.025	BSC	
M	0°	10°	0°	10°	
N	0.76	1.14	0.030	0.045	
Р	8.38	8.64	0.330	0.340	
R	6.60	6.86	0.260	0.270	
S	0.77	1.01	0.030	0.040	

MOTOROLA FAST SRAM MCM6709A

ORDERING INFORMATION (Order by Full Part Number)

	MCM	6709A	<u>X</u>	<u>XX</u>	<u> </u>	
Motorola Memory Prefix						Shipping Method (R2 = Tape and Reel, Blank = Rails)
Part Number						Speed (8 = 8 ns, 10 = 10 ns, 12 = 12 ns)
						Package (J = 300 mil SOJ)
	Full Par	Part Numbers — MCM6709AJ8			AJ8	MCM6709AJ8R2
			MC	CM6709	AJ10	MCM6709AJ10R2
			M	CM6700	Δ 112	MCM6709A 112R2

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